

### Features

- Enhancement mode transistor-Normally off power switch
- No reverse-recovery charge
- Low gate charge, low output charge
- Ultra high switching frequency
- Qualified according to JEDEC for target applications

### Applications

- AC-DC converters
- DC-DC converters
- Fast battery charging
- High density power conversion
- High efficiency power conversion

### Benefits

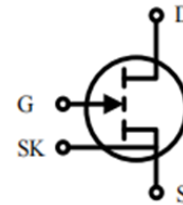
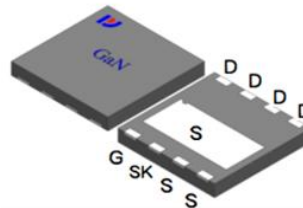
- Enable very high conversion efficiencies
- Supports high operating frequency
- Enables ultrahigh power density designs
- Improved safety & reliability due to cooler operation temperature



### Product Summary

$V_{DS}$	700V
$R_{DS(on)}$ @6.0V typ.	150m $\Omega$
$I_D$	10A

DFN8\*8



### Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
PWEG240N70W	EG240N70W	DFN8*8	Tape&Reel	13 inches	16mm	4000pcs

### Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage ( $T_j = -55^\circ\text{C}$ to $150^\circ\text{C}$ )	$V_{DSS}$	700	V
Drain to source voltage transient <sup>1</sup>	$V_{(TR)DSS}$	800	
Drain to source voltage, pulsed <sup>2</sup> $T_j = 25^\circ\text{C}$ ; total time < 10 h $T_j = 125^\circ\text{C}$ ; total time < 1 h	$V_{DSS,pulse}$	750	V
Continuous current, drain source	$I_D$	10	A
Pulsed current, drain source <sup>3</sup> $V_{GS} = 6\text{V}$ ; $T_{PULSE} = 10\ \mu\text{s}$ ; $TC = 25^\circ\text{C}$ ; $V_{GS} = 6\text{V}$ ; $T_{PULSE} = 10\ \mu\text{s}$ ; $TC = 125^\circ\text{C}$ ;	$I_{D,pulse}$	18 10	A
Gate source voltage, continuous <sup>4</sup> $T_j = -55^\circ\text{C}$ to $150^\circ\text{C}$	$V_{GS}$	-1.4~7	V
Gate source voltage, pulsed	$V_{GS,pulse}$	-20~10	V
Power dissipation	$P_{tot}$	76	W
Operating temperature	$T_j$	-55~150	$^\circ\text{C}$
Storage temperature	$T_{stg}$		
Maximum reflow soldering temperature	$T_{sold}$	260	$^\circ\text{C}$

1.  $V_{DS,transient}$  is intended for non-repetitive events,  $t_{PULSE} < 200\ \mu\text{s}$ .

2.  $V_{DS,pulse}$  is intended for repetitive pulse,  $t_{PULSE} < 100\ \text{ns}$ .

3. Limit was extracted from characterization test, not measured during production.

4. The minimum  $V_{GS}$  is clamped by ESD protection circuit, as shown in Figure 10.

**Thermal Resistance**

Parameter	Symbol	Limit value			Unit	Test Condition
		min.	typ.	max.		
Thermal resistance, junction - ambient	$R_{thJA}$	-	66	-	°C/W	-
Thermal resistance, junction - case	$R_{thJC}$	-	1.64	-	°C/W	-

**Electrical Characteristic (at  $T_j = 25\text{ }^\circ\text{C}$ , unless otherwise specified)**

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

**Static characteristics**

Gate threshold voltage	$V_{GS(th)}$	1.2	1.3	2.5	V	$I_D=11.1\text{mA}, V_{DS}=V_{GS}$ $T_j=25\text{ }^\circ\text{C}$ $T_j=150\text{ }^\circ\text{C}$
Drain-to-source leakage current	$I_{DSS}$	-	0.4	20	$\mu\text{A}$	$V_{DS}=700\text{V}, V_{GS}=0\text{V}$ $T_j=25\text{ }^\circ\text{C}$ $T_j=150\text{ }^\circ\text{C}$
Gate-source leakage current	$I_{GSS}$	-	50	-	$\mu\text{A}$	$V_{GS}=6\text{V}, V_{DS}=0\text{V}$
Drain-source on-state resistance	$R_{DS(on)}$	-	150	240	$\text{m}\Omega$	$V_{GS}=6\text{V}, I_D=3\text{A}, T_j=25\text{ }^\circ\text{C}$
		-	288	-	$\text{m}\Omega$	$V_{GS}=6\text{V}, I_D=3\text{A}, T_j=125\text{ }^\circ\text{C}$
Gate resistance	$R_G$	-	2.5	-	$\Omega$	$f = 1\text{ MHz}; \text{open drain}$

**Dynamic characteristics**

Input Capacitance	$C_{iss}$	-	80	-	pF	$V_{GS}=0\text{V}, V_{DS}=400\text{V}, f=100\text{KHz}$
Output Capacitance	$C_{oss}$	-	29	-		
Reverse Transfer Capacitance	$C_{rss}$	-	0.1	-		
Effective output capacitance, energy related <sup>1</sup>	$C_{o(er)}$	-	36	-	pF	$V_{GS}=0\text{V}, V_{DS}=0\text{V}\sim 400\text{V},$
Effective output capacitance, time related <sup>2</sup>	$C_{o(tr)}$	-	52	-		
Output charge	$Q_{oss}$	-	21	-	nC	
Turn-on delay time	$t_{d(on)}$	-	2	-	ns	$V_{GS}=6\text{V}, V_{DS}=400\text{V}, R_{G\_on(ext)}=10\Omega, I_D=6\text{A}, R_{G\_off(ext)}=2\Omega, L=318\mu\text{H},$ See Figure 22
Rise time	$t_r$	-	5	-		
Turn-off delay time	$t_{d(off)}$	-	4	-		
Fall time	$t_f$	-	6	-		

1.  $C_{o(er)}$  is the fixed capacitance that gives the same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 400 V.

2.  $C_{o(tr)}$  is the fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 400 V.

### Gate charge characteristics

Gate Total Charge	$Q_G$	-	2	-	nC	$V_{DS}=400V, I_D=3A$ $V_{GS}=0V-6V$
Gate-Source charge	$Q_{GS}$	-	0.2	-		
Gate-Drain charge	$Q_{GD}$	-	0.7	-		
Gate Plateau Voltage	$V_{Plat}$	-	2.5	-	V	$V_{DS}=400V, I_D=3A$

### Reverse Device Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Source to Drain reverse Voltage	$V_{SD}$	-	2.6	-	V	$V_{GS}=0V, I_{SD}=3A$
Pulsed current, reverse	$I_{S,pulse}$	-	-	18	A	$V_{GS}=6V, t_{PULSE}=10\mu s$
Reverse recovery charge	$Q_{rr}$	-	0	-	nC	$I_S=3A, V_{DS}=400V$
Reverse recovery time	$t_{RR}$	-	0	-	ns	
Peak reverse recovery current	$I_{rrm}$	-	0	-	A	

**Typical Performance Characteristics**

Fig 1: Typ. Output Characteristics

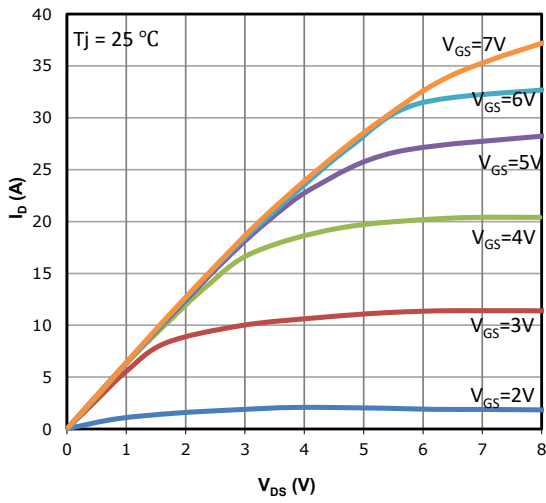


Fig 2: Typ. Output Characteristics

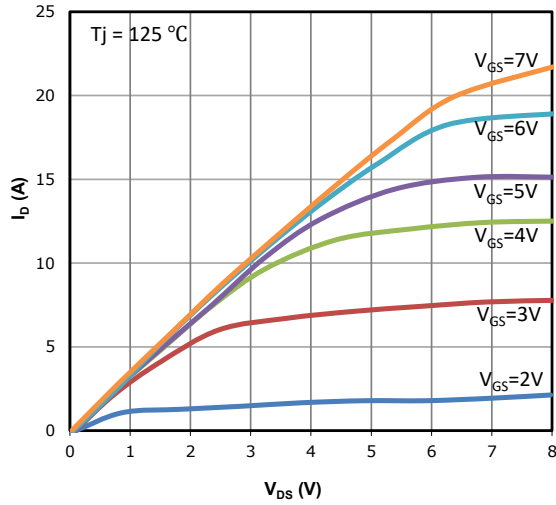


Fig 3: Typ. Drain-source on-state resistance

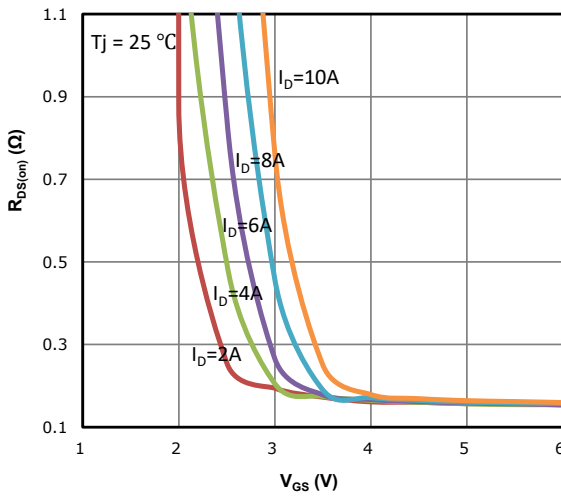


Fig 4: Typ. Drain-source on-state resistance

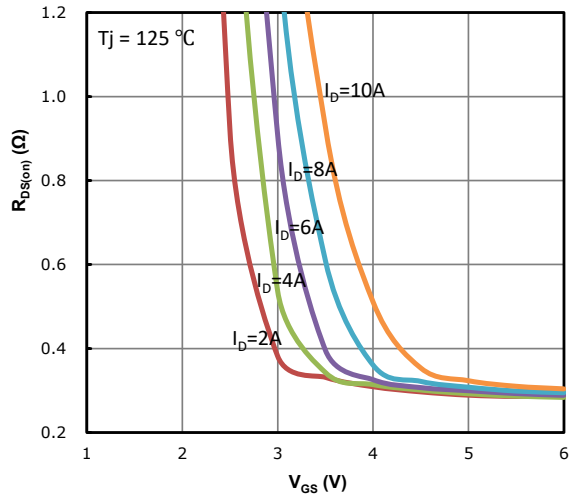


Fig 5: Typ. channel reverse characteristics

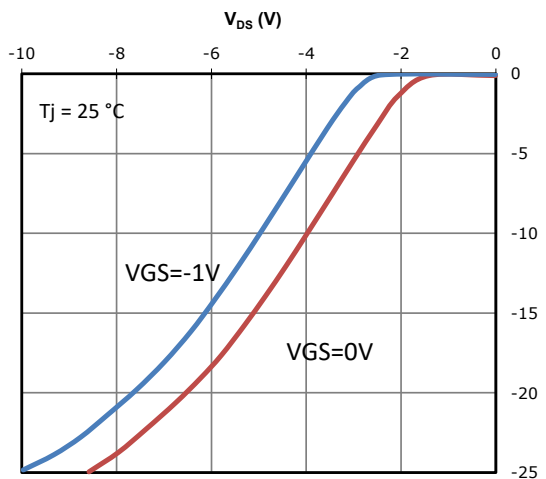


Fig 6: Typ. channel reverse characteristics

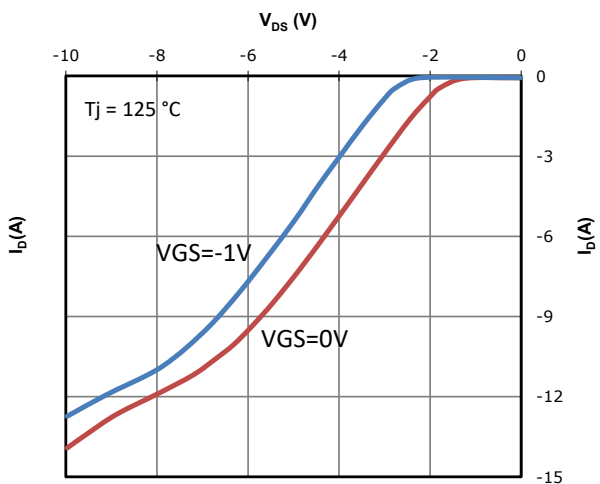


Fig 7:  
 Typ. channel reverse characteristics

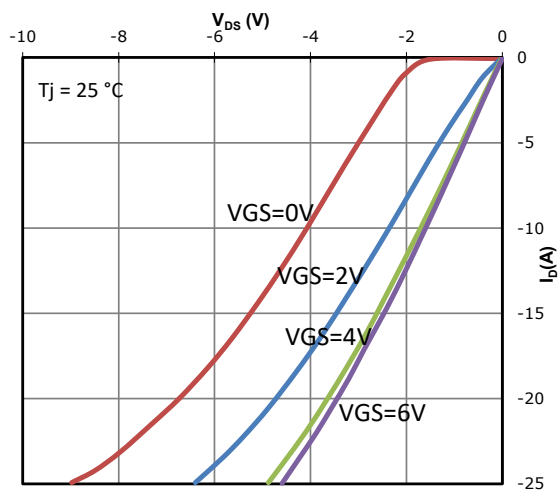


Fig 8:  
 Typ. channel reverse characteristics

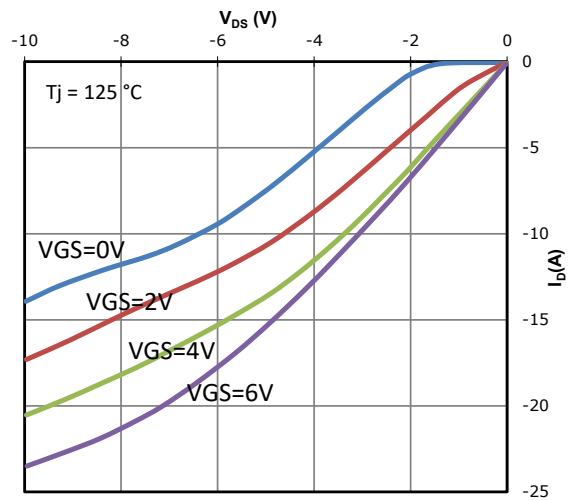


Fig 9: Typ. Transfer Characteristics

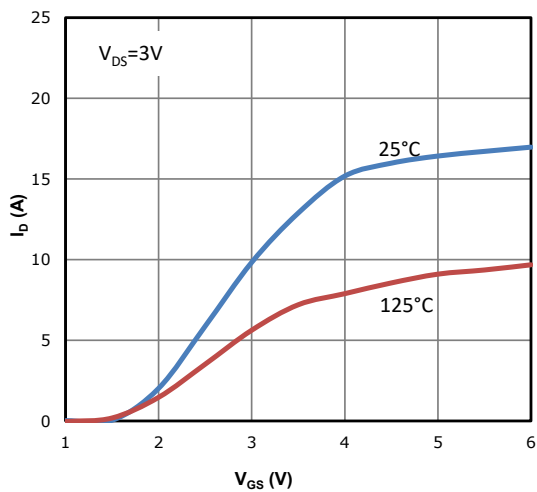


Fig 10: Typ. Gate-to-Source leakage

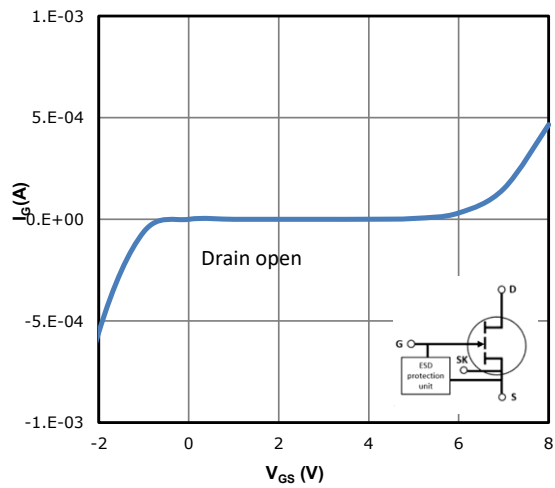


Fig 11: Drain-source leakage characteristics

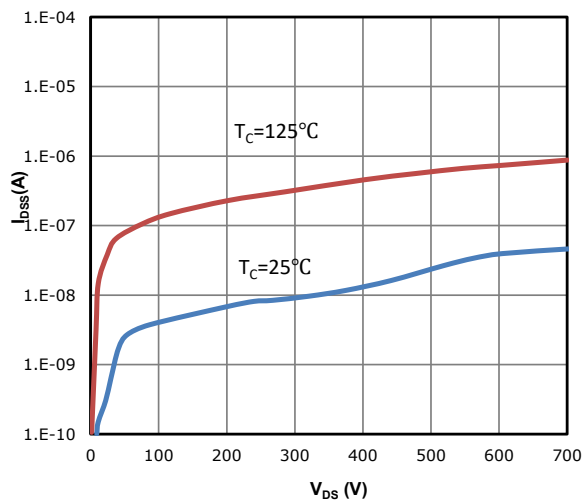


Fig 12: Vgs(th) vs. Temperature

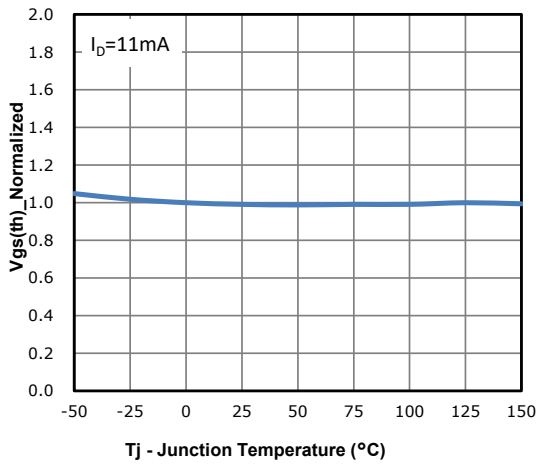


Fig 13: Rds(on) vs. Temperature

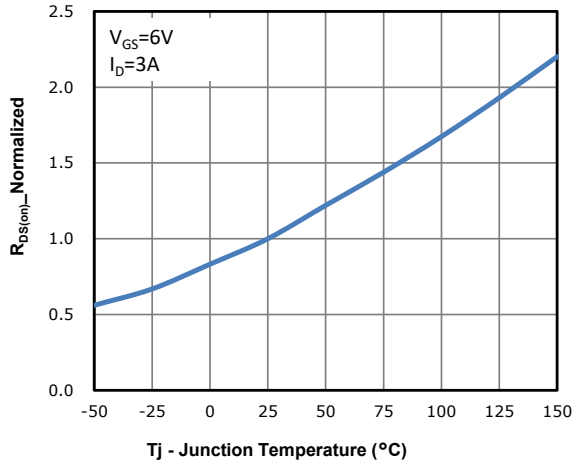


Fig 14: Power Dissipation

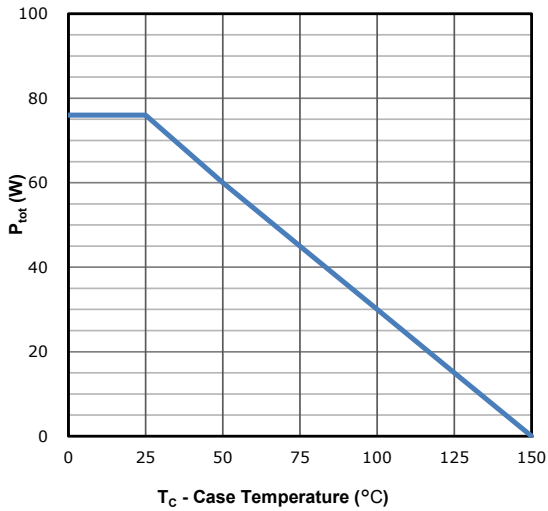


Fig 15: Max. Transient Thermal Impedance

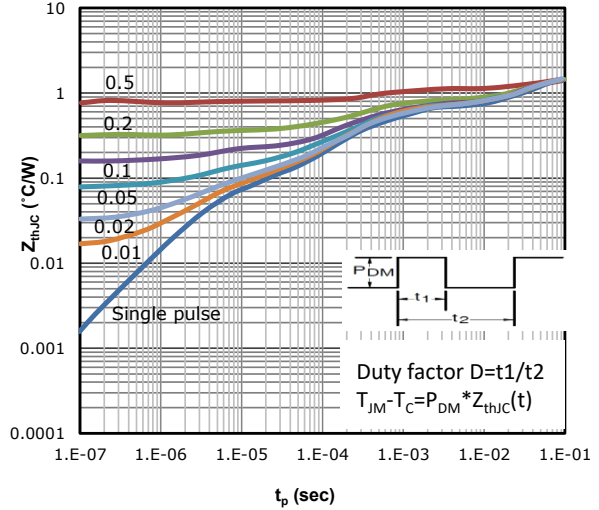


Fig 16: Safe Operating Area

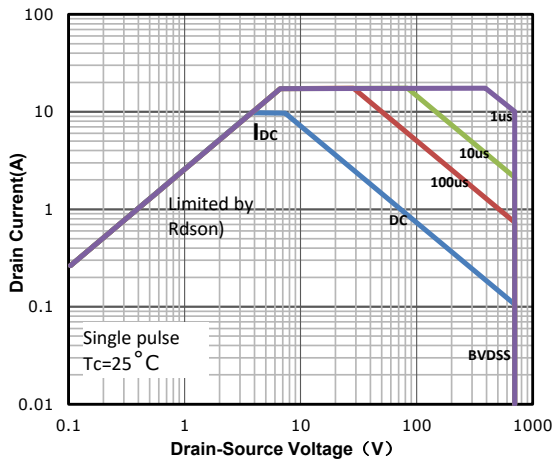


Fig 17: Safe Operating Area

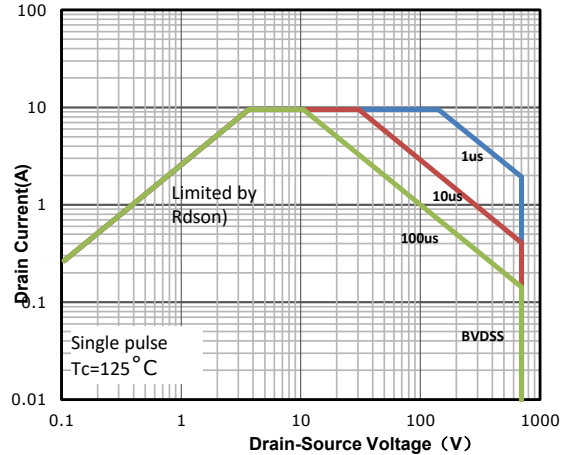


Fig 18: Gate Charge Characteristics

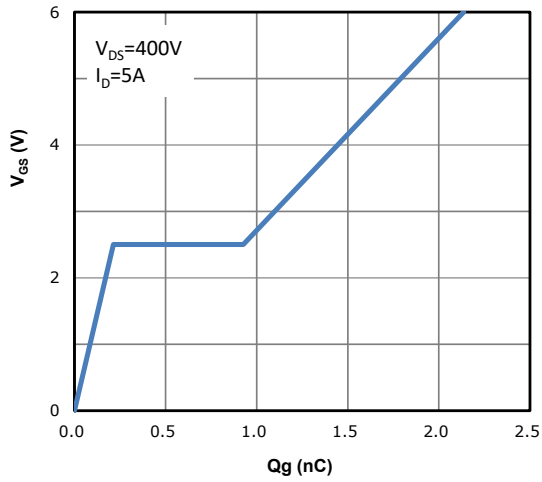


Fig 19: Capacitance Characteristics

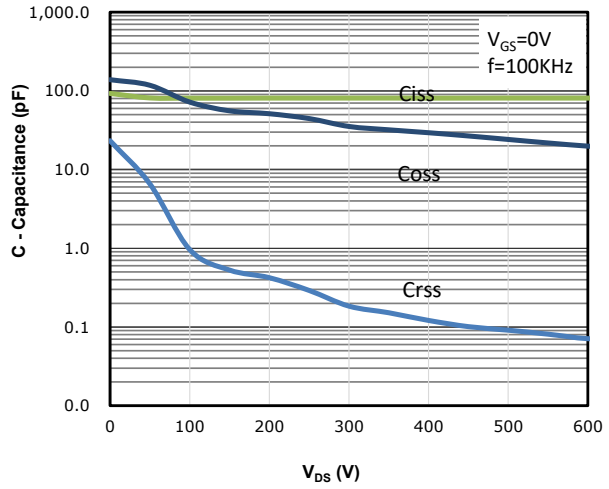


Fig 20: Typ. output charge

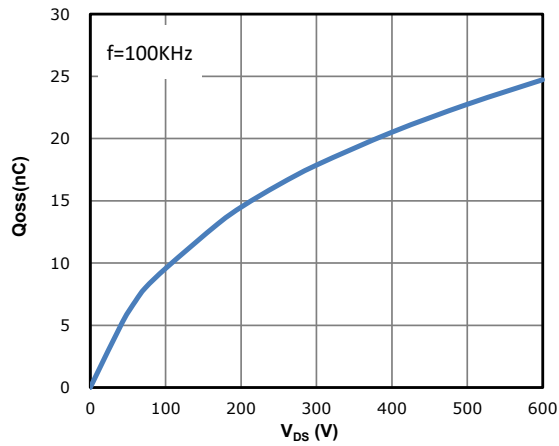
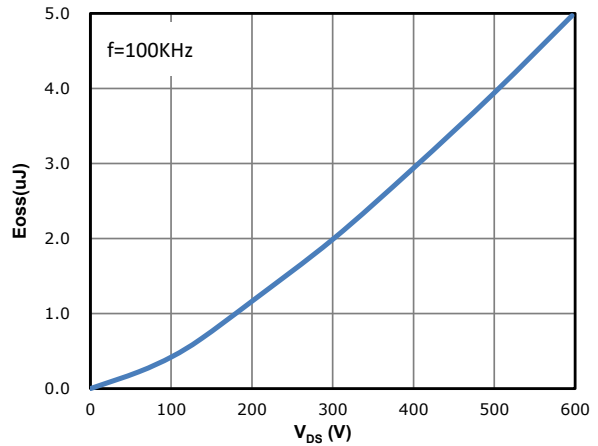
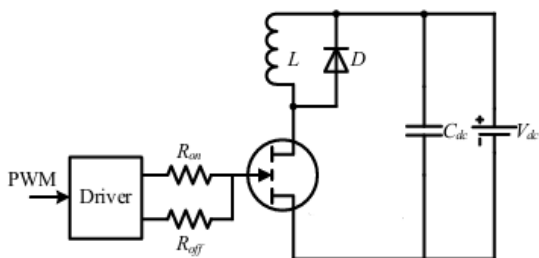


Fig 21: Typ.  $C_{OSS}$  stored Energy



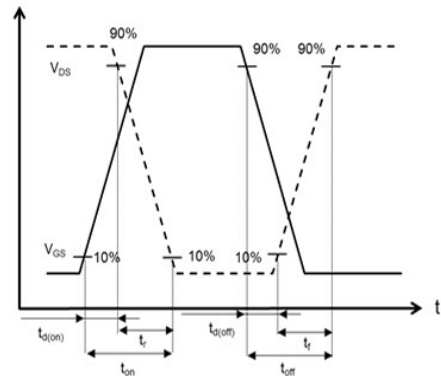
**Test Circuit & Waveform**

Fig 22: Typ. Switching time with inductive load

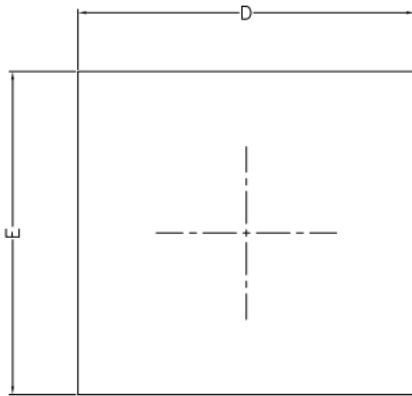


$V_{DS}=400V$ ,  $I_D=6A$ ,  $L=318\mu H$ ,  
 $V_{GS}=6V$ ,  $R_{on}=10\Omega$ ,  $R_{off}=2\Omega$

Fig 23: Typ. Switching times waveform



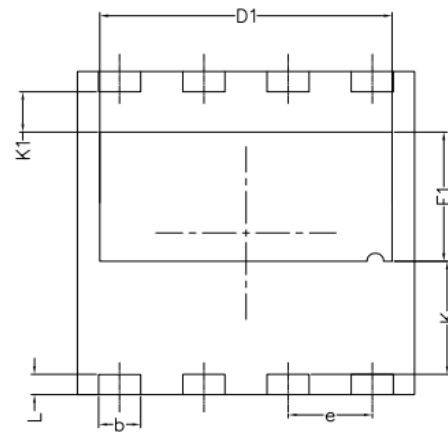
**Package Outline: DFN8\*8**



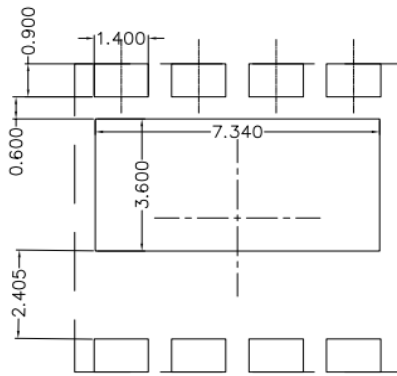
FRONT VIEW



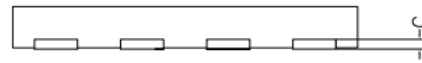
SIDE VIEW



BOTTOM VIEW



RECOMMENDED LAND PATTERN



TOP VIEW

DIMENS ION	MILLIMETERS		
	MIN	NOM	MAX
A	0.95	1.0	1.35
A1	0	0.02	0.05
C	0.203REF		
b	0.9	1.0	1.1
D	7.9	8.0	8.1
D1	6.84	6.94	7.04
E	7.9	8.0	8.1
E1	3.1	3.2	3.3
e	2.0BSC		
K	2.8REF		
K1	0.9	1.0	1.1
L	0.45	0.5	0.55



---

### Disclaimer

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Buyer is responsible for its products and applications using PingWei products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by PingWei.

“Typical” parameters which may be provided in PingWei data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including “Typicals” must be validated for each customer application by customer’s technical experts

ALL PRODUCT, PRODUCT SPECIFICATIONS AND DATA ARE SUBJECT TO CHANGE WITHOUT NOTICE TO IMPROVE RELIABILITY, FUNCTION OR DESIGN OR OTHERWISE